Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	327	(adjust$3 with voltage) same (test$3 with memory)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/29 15:36
L2	19	l1 and ((pullup or pull-up) with transistor$1)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/29 15:37
L3	10	365/201,200.ccls. and test$3 and ((pullup or pull-up) with transistor$1) and SRAM and ((modif$4 or adjust$3 or variable$1) with bias)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/29 15:41
L6	53	365/201,200,230.06,226,190, 203-205,194,154,156.ccls. and (weak with test) and SRAM and transistor$1	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/29 15:44
L7	5	365/201,200,230.06,226,190, 203-205,194,154,156.ccls. and (weak with test) and SRAM and (transistor$1 with (fuse$1 or antifuse$1))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/29 15:45
L8	51827	SRAM and memory	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/29 15:45
L9	15872	l8 and test$3	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/29 15:45
L10	25	l9 and ((weak adj write adj test adj mode) or WWTM)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/29 15:46

L11	325	I9 and bias near2 generat$3	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/29 15:47
L12	232	I11 and driver	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/29 15:47
L13	232	I12 and voltage	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/29 15:47
L14	226	I13 and transistor	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/29 15:4
L15	113	I14 and (pullup or pull-up)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/29 15:4
L16	98	I15 and (pulldown or pull-down)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/29 15:49
L17	69	I16 and metal$1	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/29 15:49
L18	3	I9 and (metal-program$4 or (metal adj program$4))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/29 15:50

L19	27	test$3 and (metal-program$4 or (metal adj program$4))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/29 15:51
L20	16	l19 and memory	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/29 15:50
L21	9	l20 and (bias$3 or voltage$1)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/29 15:51
L22	4	(bias adj2 generator) and (metal-program$4 or (metal adj program$4))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/29 15:53
L23	4966	circuit$3 same (internal adj voltage)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/29 16:04
L24	34	l1 and l23	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/29 15:54
L25	49	circuit$3 same (internal adj voltage) same ((pullup or pull-up) with transistor$1)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/29 16:05
L26	16	circuit$3 same (internal adj voltage) same ((pullup or pull-up) with transistor$1) same ((pulldown or pull-down) with transistor$1)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/29 16:05